



Committee on Education (Standing Committee of the NPC)

Chair: Deborah Prince, Underwriters Laboratories
Staff: Lisa Rajchel

Voting Members: (33)

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Ms. Joyce Abrams, ASHRAE (2012)
Mr. Thomas Applegate, ACTE (2012)
Mr. Vince Baclawski, NEMA (2012)
Ms. Monica Barone, Qualcomm (2012)
Mr. Monte Bogatz, IAPMO (2014)
Ms. Ann Brigida, InfoComm International (2014)
Mr. Donald Deutsch, Oracle (2012)
Dr. Stephen J. Elliott, Purdue University (2012)
Ms. Joy Fitzpatrick, Boeing Company (2012)
Dr. Richard Forselius, UTC/Sikorsky Aircraft Corp. (2012)
Ms. Dorothy Harris, ICC (2012)
Mr. Robert D. Hunter, P.E., Robert Hunter Assoc. (2012)
Mr. Frankie S. Jones, AT&T Business Learning Services (2012)
Mr. Stuart Karasik, Utilities Group (2012)
Ms. Liz Kerrigan, Infectious Diseases, ATCC (2012)
Mr. Stephen Kwan, San Jose University (2013)
Mr. Edward F. Mikowski, Jr., ECA (2012)
Ms. Ashley Moore, U.S. Dept. of Homeland Security (2012)
Dr. Christine Neiro, Professional Testing Inc. (2013)
Mr. Jim Olshefsky, ASTM International (2013)
Dr. Katherine D. Seelman, Univ. of Pittsburgh (2012)
Dr. Timothy Smith, University of Minnesota (2012)
Ms. Nancy Stark, Clinical Device Group (2012)
Ms. Jennifer Stradtman, U.S. DoC/ITA (2013)
Mr. Manfred Straehle, Green Building Certificate Inst. (2013)
Ms. Susan Tatiner, IEEE (2012)
Mr. Lee Webster, Society for HR Management (2012)
Mr. Jefferson Welch, Carnegie Mellon University (2012)
Mr. Philip Wennblom, Intel (2012)
Ms. Trudie Williams, U.S. DoD (2012)
Mr. George Willingmyre, GTW Associates (2012)
Mr. Donald Yarbrough, Educational Evaluation (2012)

Non-voting Members: (25)

Mr. John Bagby, Penn State University
Mr. Dan Bart, Valley View Corporation
Mr. Brad Biddle, Intel
Mr. Keith Bird, Corporation for a Skilled Workforce
Mr. Lawrence Busch, Michigan State University
Ms. Carola Emelius-Swartz, Qualcomm
Mr. Jorge Contreras, Contreras Legal Strategy LLC
Ms. Betsy Fanning, AIIM
Ms. Latonia Gordon, Microsoft
Ms. Erin Grossi, Underwriters Laboratories
Mr. Bruce Harding, Purdue University
Mr. Stan Hazan, NSF International
Mr. David Hernandez, American Welding Society
Ms. Susan Hoyler, Qualcomm
Mr. Daryl Hunt, Eastman Kodak
Mr. Tim Koczanski, Department of Defense
Mr. John Kulick, Siemens Corporate Research
Mr. Bruce Mahone, SAE International
Ms. Jennifer McClain, IEEE
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Mr. Steve Mills, IEEE
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